April 2008



FDD6676AS

30V N-Channel PowerTrench® SyncFET™

General Description

The FDD6676AS is designed to replace a single MOSFET and Schottky diode in synchronous DC:DC power supplies. This 30V MOSFET is designed to maximize power conversion efficiency, providing a low $R_{\text{DS(ON)}}$ and low gate charge. The FDD6676AS includes a patented combination of a MOSFET monolithically integrated with a Schottky diode using Fairchild's monolithic SyncFET technology.

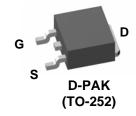
Applications

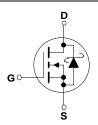
- DC/DC converter
- · Low side notebook

Features

- 90 A, 30 V $R_{DS(ON)} = 5.7 \text{ m}\Omega$ @ $V_{GS} = 10 \text{ V}$ $R_{DS(ON)} = 7.1 \text{ m}\Omega$ @ $V_{GS} = 4.5 \text{ V}$
- Includes SyncFET schottky body diode
- Low gate charge (46nC typical)
- $\bullet~$ High performance trench technology for extremely low $R_{\text{DS}(\text{ON})}$
- High power and current handling capability
- RoHS Compliant







Absolute Maximum Ratings T_A=25°C unless otherwise noted

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Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		30	V
V _{GSS}	Gate-Source Voltage		±20	V
I _D	Drain Current - Continuous	(Note 3)	90	А
	- Pulsed	(Note 1a)	100	
P _D	Power Dissipation for Single Operation	(Note 1)	70	W
		(Note 1a)	3.1	
		(Note 1b)	1.3	
T _J , T _{STG}	Operating and Storage Junction Temperat	ture Range	-55 to +150	°C

Thermal Characteristics

R _θ JC	Thermal Resistance, Junction-to-Case	(Note 1)	1.8	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	40	°C/W
R _{e,JA}	Thermal Resistance, Junction-to-Ambient	(Note 1b)	96	°C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDD6676AS	FDD6676AS	13"	12mm	2500 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-Sc	ource Avalanche Ratings (Not	e 2)	I		I	ı
W _{DSS}	Drain-Source Avalanche Energy	Single Pulse, $V_{DD} = 15 \text{ V}$, $I_D = 16 \text{A}$		108	250	mJ
I _{AR}	Drain-Source Avalanche Current				16	Α
Off Char	acteristics	•	•	•		
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 1 \text{ mA}$	30			V
ΔBV _{DSS} ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 10 mA, Referenced to 25°C		31		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 24 V, V _{GS} = 0 V			500	μΑ
		V _{DS} = 24 V, V _{GS} = 0 V, T _J =125°C		11		mA
I _{GSS}	Gate-Body Leakage	$V_{GS} = \pm 20 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			±100	nA
On Char	acteristics (Note 2)	•				•
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 1$ mA	1	1.5	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	I _D = 10 mA, Referenced to 25°C		-3.6		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance	$V_{GS} = 10 \text{ V}, \ I_D = 16 \text{ A}$ $V_{GS} = 4.5 \text{ V}, \ I_D = 15 \text{ A}$ $V_{GS} = 10 \text{ V}, \ I_D = 16 \text{ A}, T_J = 125^{\circ}\text{C}$		4.7 5.8 6.7	5.7 7.1 8.4	mΩ
g _{FS}	Forward Transconductance	$V_{DS} = 5 \text{ V}, \qquad I_{D} = 16 \text{ A}$		61		S
Dvnami	Characteristics					
C _{iss}	Input Capacitance			2500		pF
C _{oss}	Output Capacitance	$V_{DS} = 15 \text{ V}, \qquad V_{GS} = 0 \text{ V},$		710		pF
C _{rss}	Reverse Transfer Capacitance	f = 1.0 MHz		270		pF
R _G	Gate Resistance	$V_{GS} = 0 V$, $f = 1.0 MHz$		1.6		Ω
Switchir	ng Characteristics (Note 2)	•				•
t _{d(on)}	Turn-On Delay Time			12	21	ns
t _r	Turn-On Rise Time	$V_{DD} = 15 \text{ V}, \qquad I_{D} = 1 \text{ A},$		12	22	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		46	74	ns
t _f	Turn-Off Fall Time	1		28	44	ns
t _{d(on)}	Turn-On Delay Time			20	32	ns
t _r	Turn-On Rise Time	$V_{DD} = 15 \text{ V}, \qquad I_{D} = 1 \text{ A},$		24	38	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = 4.5 \text{ V}, \qquad R_{GEN} = 6 \Omega$		35	56	ns
t _f	Turn-Off Fall Time	7		27	43	ns
Q _{g(TOT)}	Total Gate Charge, Vgs = 10V			46	64	nC
Qg	Total Gate Charge, Vgs = 5V	- V _{DS} = 15 V, I _D = 16 A		25	35	nC
Q _{gs}	Gate-Source Charge	$\int_{0}^{\infty} \nabla DS = 10 \text{ V}, \qquad \text{ID} = 10 \text{ A}$		7		nC
Q_{gd}	Gate-Drain Charge			9		nC

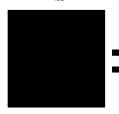
Electrical Characteristics (continued)

 $T_{\Delta} = 25^{\circ}$ C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-S	ource Diode Characteristics	and Maximum Ratings				
Is	Maximum Continuous Drain-Source	Diode Forward Current			3.5	Α
V _{SD}	Drain–Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 3.5 \text{ A} \text{(Note 2)}$		0.4	0.7	V
t_{RR}	Diode Reverse Recovery Time			25		ns
I _{RM}	Maximum Recovery Current	$dI_F/dt = 300A/us, I_F = 16A$		1.9		Α
Q _{RR}	Diode Reverse Recovery Charge			24		nC

Notes

1. R_{0JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{0JC} is guaranteed by design while R_{0CA} is determined by the user's board design.



a) $R_{\theta JA} = 40$ °C/W when mounted on a 1in^2 pad of 2 oz copper



b) $R_{\theta JA} = 96^{\circ}C/W$ when mounted on a minimum pad.

Scale 1:1 on letter size paper

- 2. Pulse Test: Pulse Width < 300μs, Duty Cycle < 2.0%
- 3. Maximum current is calculated as: $\sqrt{\frac{P_D}{R_{DS(ON)}}}$

where P_D is maximum power dissipation at $T_C = 25^{\circ}C$ and $R_{DS(on)}$ is at $T_{J(max)}$ and $V_{GS} = 10V$. Package current limitation is 21A

Typical Characteristics

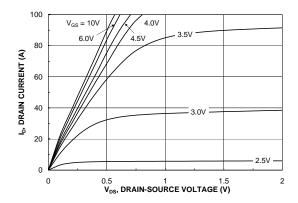
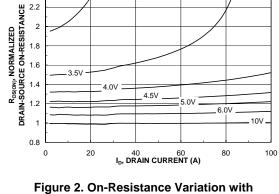


Figure 1. On-Region Characteristics



 $V_{GS} = 3.0V$

Figure 2. On-Resistance Variation with Drain Current and Gate Voltage

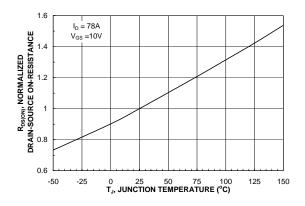


Figure 3. On-Resistance Variation with Temperature

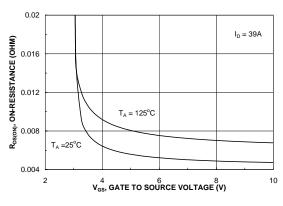


Figure 4. On-Resistance Variation with Gate-to-Source Voltage

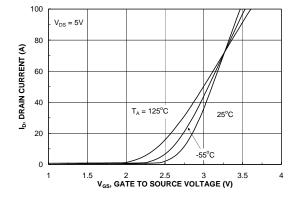


Figure 5. Transfer Characteristics

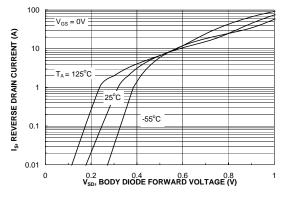
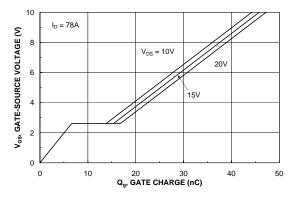


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature

Typical Characteristics



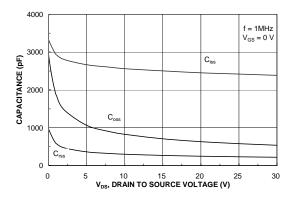


Figure 7. Gate Charge Characteristics

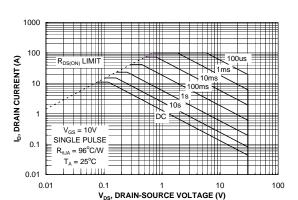


Figure 8. Capacitance Characteristics

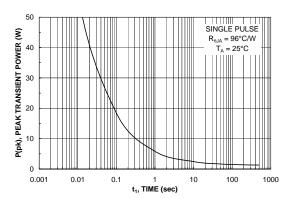


Figure 9. Maximum Safe Operating Area



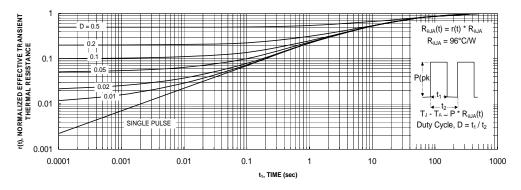


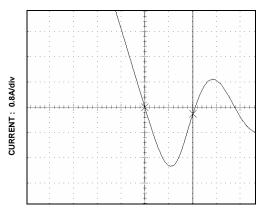
Figure 11. Transient Thermal Response Curve

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

Typical Characteristics (continued)

SyncFET Schottky Body Diode Characteristics

Fairchild's SyncFET process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 12 shows the reverse recovery characteristic of the FDD6676AS.



TIME: 12.5ns/div

Figure 12. FDD6676AS SyncFET body diode reverse recovery characteristic.

For comparison purposes, Figure 13 shows the reverse recovery characteristics of the body diode of an equivalent size MOSFET produced without SyncFET (FDD6676A).

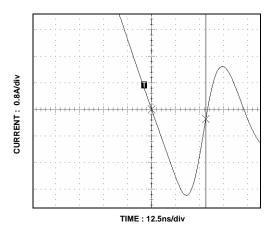


Figure 13. Non-SyncFET (FDD6676A) body diode reverse recovery characteristic.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

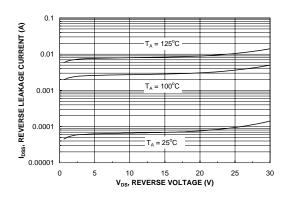
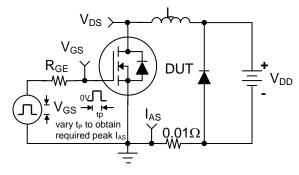


Figure 14. SyncFET body diode reverse leakage versus drain-source voltage and temperature.

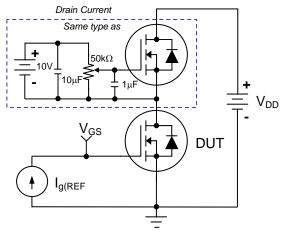
Typical Characteristics



BV_{DSS}
V_{DD}
V_{DD}

Figure 15. Unclamped Inductive Load Test Circuit

Figure 16. Unclamped Inductive Waveforms



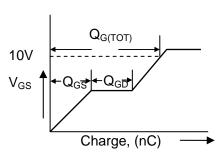
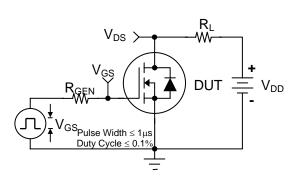


Figure 17. Gate Charge Test Circuit

Figure 18. Gate Charge Waveform



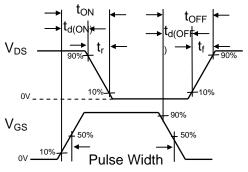


Figure 19. Switching Time Test Circuit

Figure 20. Switching Time Waveforms





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